



BSI Standards Publication

**Surface chemical analysis — Secondary ion
mass spectrometry — Method for determining
yield volume in argon cluster sputter
depth profiling of organic materials**

National foreword

This British Standard is the UK implementation of [ISO 22415:2019](#).

The UK participation in its preparation was entrusted to Technical Committee CII/60, Surface chemical analysis.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

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Amendments/corrigenda issued since publication

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